

**Search Notes**

Application No.

10/034,320

Examiner

Granvill D Lee, Jr

Applicant(s)

PARK ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner
438	11,14-15,25-26	4/25/2003	GL
438	51,64	4/25/2003	GL
438	106,478	4/25/2003	GL
438	238-39	4/25/2003	GL
257	355,678	4/25/2003	GL
257	778-780	4/25/2003	GL
257	48	4/25/2003	GL
above	updated	11/13/2003	GL
above	updated	6/1/2004	GL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
438	11,14-15	6/1/2004	GL
438	106	6/1/2004	GL
257	48,678	6/1/2004	GL
716/4		6/1/2004	GL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
option pad,esd,power pin,sram,control signal,package (level) test, ball array,burn-in,I/O & par. test.	4/20/2003	GL
isolating (power) pin,ground pin,power lines,power bus,voltage pin keeper circuit	11/13/2003	GL
above updated	6/1/2004	GL